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Understanding Embedded - Microprocessors

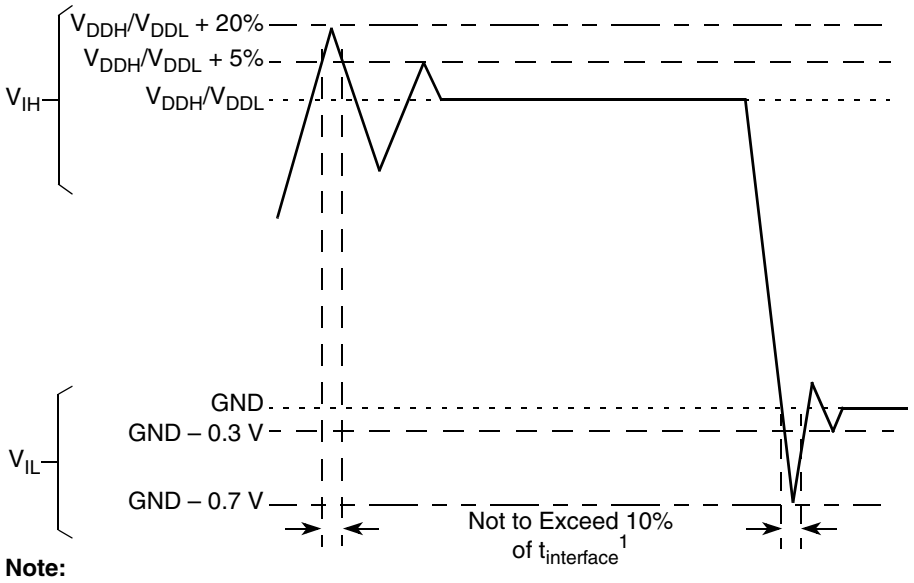
Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	MPC8xx
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	80MHz
Co-Processors/DSP	Communications; CPM
RAM Controllers	DRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10Mbps (2), 10/100Mbps (1)
SATA	-
USB	-
Voltage - I/O	3.3V
Operating Temperature	0°C ~ 95°C (TA)
Security Features	-
Package / Case	357-BBGA
Supplier Device Package	357-PBGA (25x25)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc860dpvr80d4

Figure 1 shows the undershoot and overshoot voltages at the interface of the MPC860.



Note:
1. $t_{interface}$ refers to the clock period associated with the bus clock interface.

Figure 1. Undershoot/Overshoot Voltage for V_{DDH} and V_{DDL}

4 Thermal Characteristics

Table 3. Package Description

Package Designator	Package Code (Case No.)	Package Description
ZP	5050 (1103-01)	PBGA 357 25*25*0.9P1.27
ZQ/VR	5058 (1103D-02)	PBGA 357 25*25*1.2P1.27

Table 4 shows the thermal characteristics for the MPC860.

Table 4. MPC860 Thermal Resistance Data

Rating	Environment		Symbol	ZP MPC860P	ZQ / VR MPC860P	Unit
Mold Compound Thickness				0.85	1.15	mm
Junction-to-ambient [1]	Natural convection	Single-layer board (1s)	$R_{\theta JA}$ [2]	34	34	°C/W
		Four-layer board (2s2p)	$R_{\theta JMA}$ [3]	22	22	
	Airflow (200 ft/min)	Single-layer board (1s)	$R_{\theta JMA}$ [3]	27	27	
		Four-layer board (2s2p)	$R_{\theta JMA}$ [3]	18	18	
Junction-to-board [4]			$R_{\theta JB}$	14	13	
Junction-to-case [5]			$R_{\theta JC}$	6	8	
Junction-to-package top [6]	Natural convection		Ψ_{JT}	2	2	

1 Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, airflow, power dissipation of other components on the board, and board thermal resistance.

2 Per SEMI G38-87 and JEDEC JESD51-2 with the single-layer board horizontal.

3 Per JEDEC JESD51-6 with the board horizontal.

4 Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

5 Indicates the average thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the cold plate temperature used for the case temperature. For exposed pad packages where the pad would be expected to be soldered, junction-to-case thermal resistance is a simulated value from the junction to the exposed pad without contact resistance.

6 Thermal characterization parameter indicating the temperature difference between the package top and the junction temperature per JEDEC JESD51-2.

7 Thermal Calculation and Measurement

For the following discussions, $P_D = (V_{DD} \times I_{DD}) + PI/O$, where PI/O is the power dissipation of the I/O drivers.

7.1 Estimation with Junction-to-Ambient Thermal Resistance

An estimation of the chip junction temperature, T_J, in ºC can be obtained from the equation:

$$T_J = T_A + (R_{\theta JA} \times P_D)$$

where:

T_A = ambient temperature (ºC)

$R_{\theta JA}$ = package junction-to-ambient thermal resistance (ºC/W)

P_D = power dissipation in package

The junction-to-ambient thermal resistance is an industry standard value which provides a quick and easy estimation of thermal performance. However, the answer is only an estimate; test cases have demonstrated that errors of a factor of two (in the quantity $T_J - T_A$) are possible.

7.2 Estimation with Junction-to-Case Thermal Resistance

Historically, the thermal resistance has frequently been expressed as the sum of a junction-to-case thermal resistance and a case-to-ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

where:

$R_{\theta JA}$ = junction-to-ambient thermal resistance (ºC/W)

$R_{\theta JC}$ = junction-to-case thermal resistance (ºC/W)

$R_{\theta CA}$ = case-to-ambient thermal resistance (ºC/W)

$R_{\theta JC}$ is device related and cannot be influenced by the user. The user adjusts the thermal environment to affect the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the airflow around the device, add a heat sink, change the mounting arrangement on the printed-circuit board, or change the thermal dissipation on the printed-circuit board surrounding the device. This thermal model is most useful for ceramic packages with heat sinks where some 90% of the heat flows through the case and the heat sink to the ambient environment. For most packages, a better model is required.

7.3 Estimation with Junction-to-Board Thermal Resistance

A simple package thermal model which has demonstrated reasonable accuracy (about 20%) is a two-resistor model consisting of a junction-to-board and a junction-to-case thermal resistance. The junction-to-case thermal resistance covers the situation where a heat sink is used or where a substantial amount of heat is dissipated from the top of the package. The junction-to-board thermal resistance describes the thermal performance when most of the heat is conducted to the printed-circuit board. It has been observed that the thermal performance of most plastic packages, especially PBGA packages, is strongly dependent on the board temperature; see Figure 2.

Figure 9 provides the timing for the input data controlled by the UPM for data beats where DLT3 = 1 in the UPM RAM words. (This is only the case where data is latched on the falling edge of CLKOUT.)

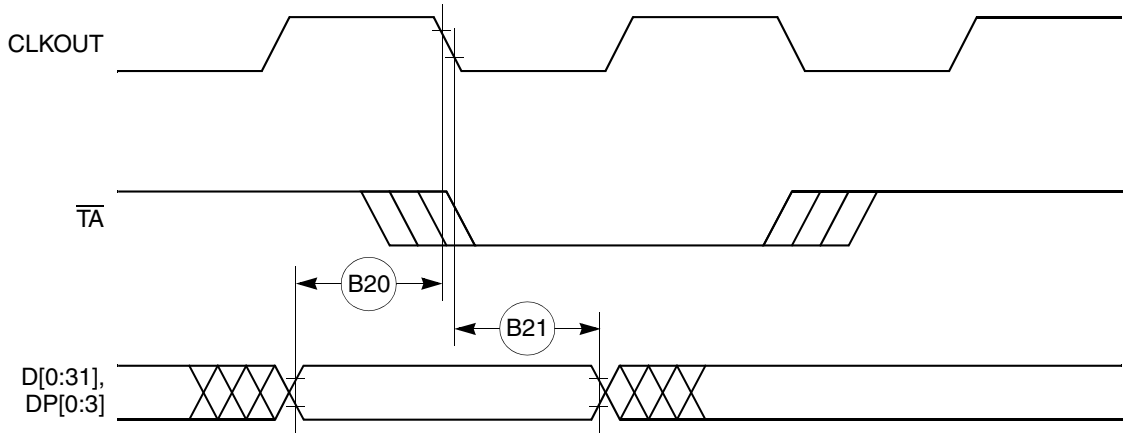


Figure 9. Input Data Timing when Controlled by UPM in the Memory Controller and DLT3 = 1

Figure 10 through Figure 13 provide the timing for the external bus read controlled by various GPCM factors.

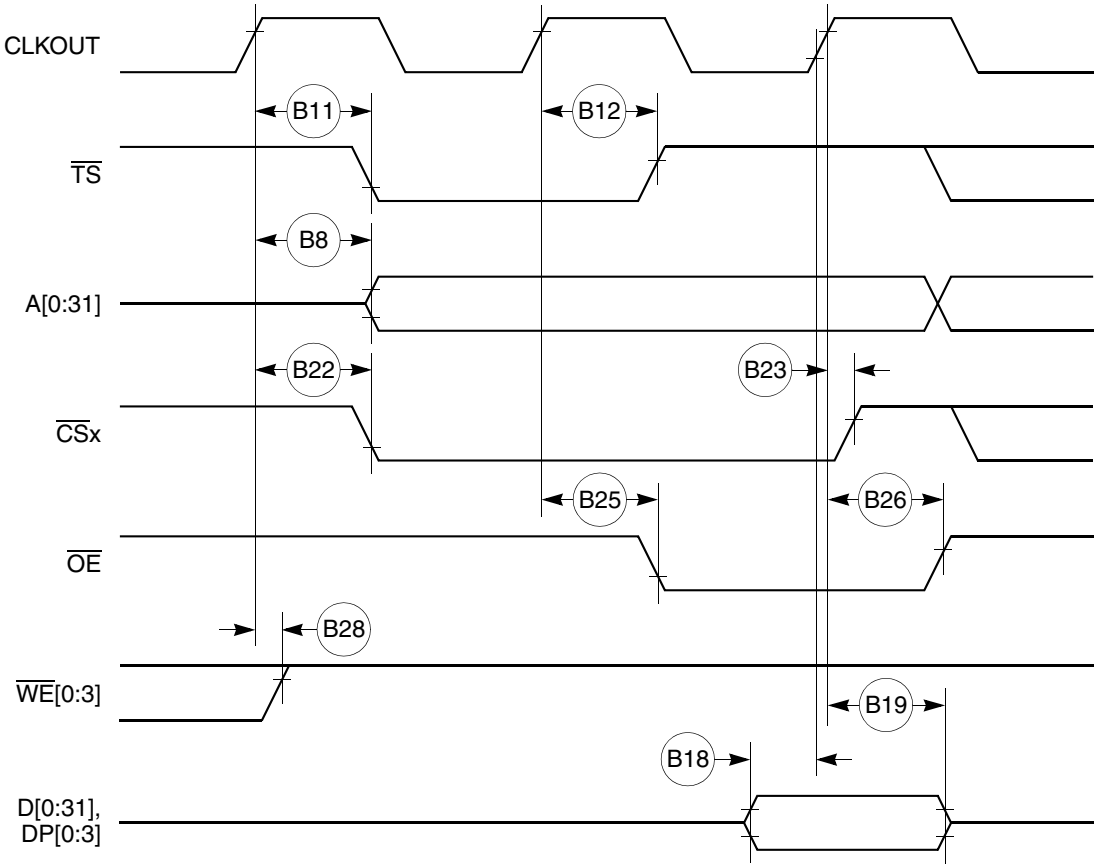


Figure 10. External Bus Read Timing (GPCM Controlled—ACS = 00)

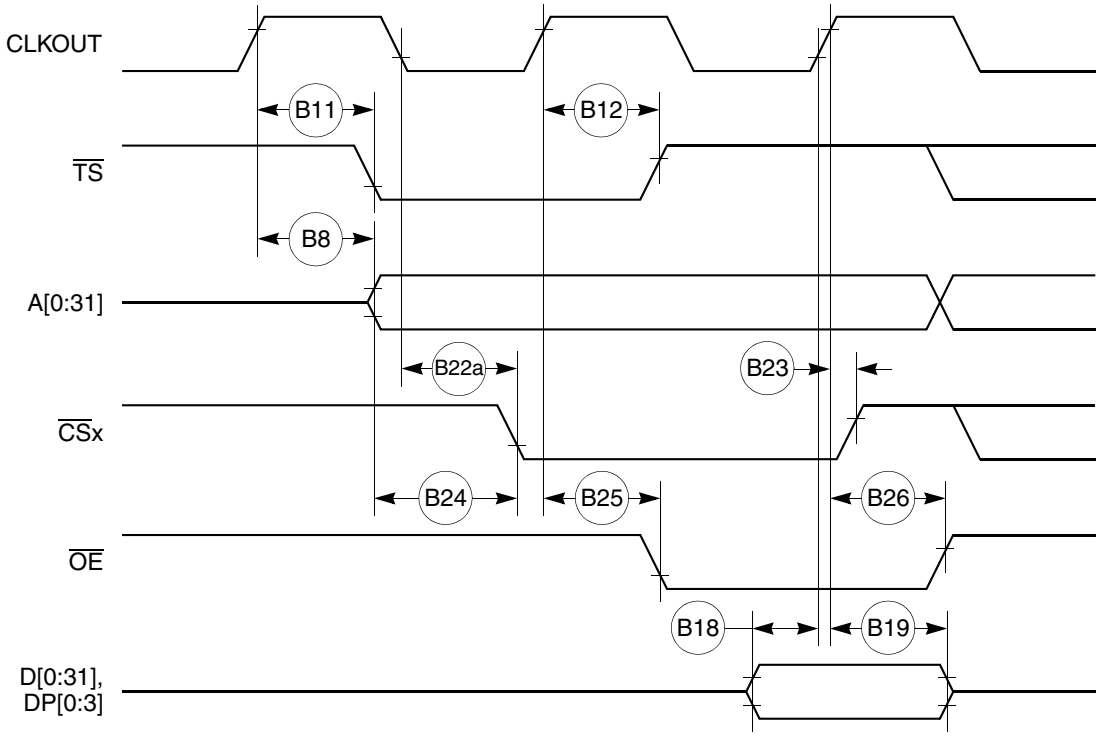


Figure 11. External Bus Read Timing (GPCM Controlled—TRLX = 0, ACS = 10)

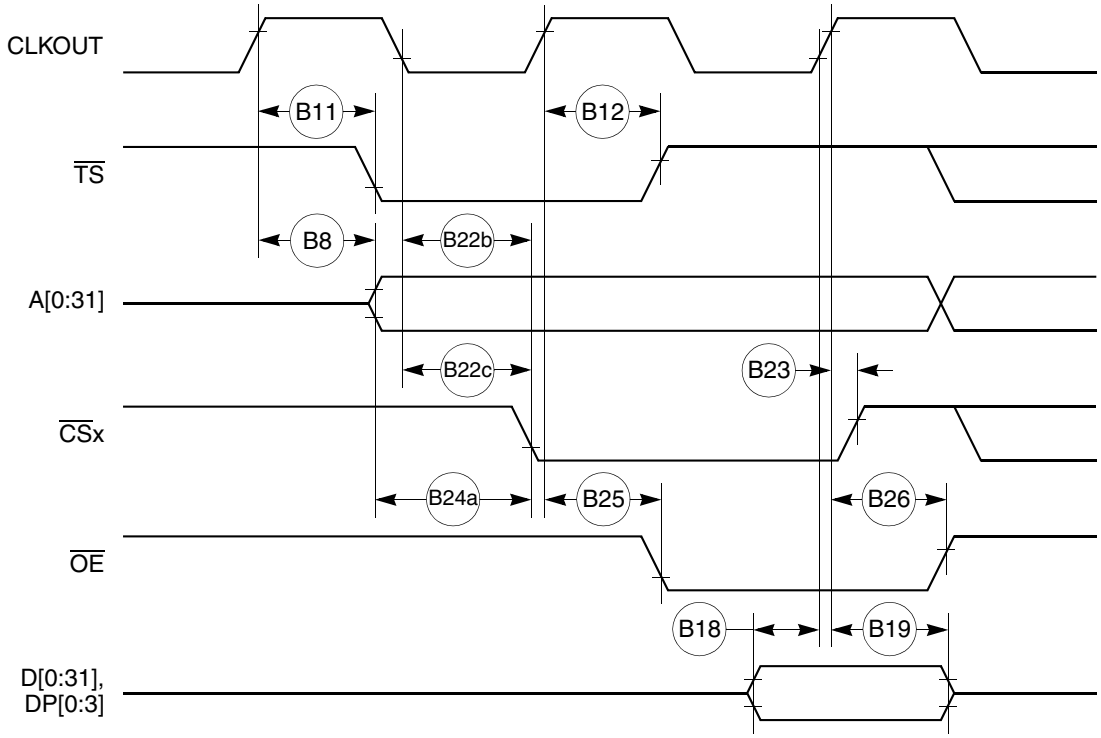


Figure 12. External Bus Read Timing (GPCM Controlled—TRLX = 0, ACS = 11)

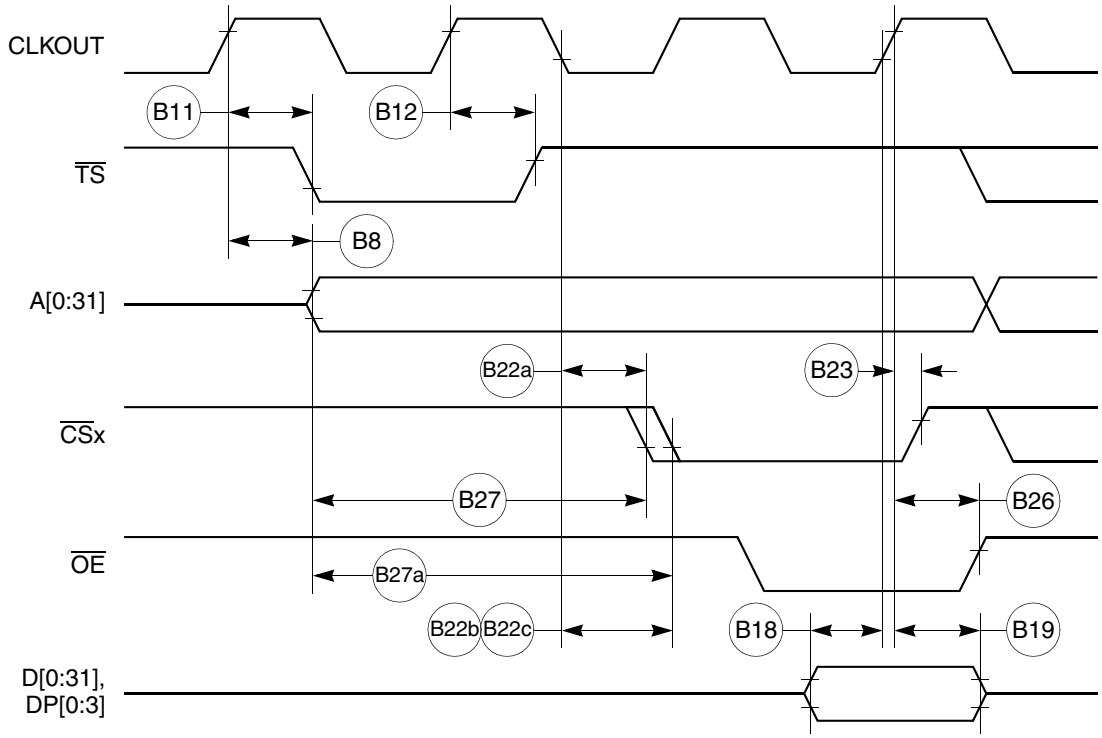


Figure 13. External Bus Read Timing (GPCM Controlled—TRLX = 0 or 1, ACS = 10, ACS = 11)

Table 12 shows the reset timing for the MPC860.

Table 12. Reset Timing

Num	Characteristic	33 MHz		40 MHz		50 MHz		66 MHz		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
R69	CLKOUT to $\overline{\text{HRESET}}$ high impedance	—	20.00	—	20.00	—	20.00	—	20.00	ns
R70	CLKOUT to $\overline{\text{SRESET}}$ high impedance	—	20.00	—	20.00	—	20.00	—	20.00	ns
R71	$\overline{\text{RSTCONF}}$ pulse width	515.15	—	425.00		340.00	—	257.58	—	ns
R72	—	—	—	—	—	—	—	—	—	
R73	Configuration data to HRESET rising edge setup time	504.55	—	425.00	—	350.00	—	277.27	—	ns
R74	Configuration data to $\overline{\text{RSTCONF}}$ rising edge setup time	350.00	—	350.00	—	350.00	—	350.00	—	ns
R75	Configuration data hold time after $\overline{\text{RSTCONF}}$ negation	0.00	—	0.00	—	0.00	—	0.00	—	ns
R76	Configuration data hold time after $\overline{\text{HRESET}}$ negation	0.00	—	0.00	—	0.00	—	0.00	—	ns
R77	$\overline{\text{HRESET}}$ and $\overline{\text{RSTCONF}}$ asserted to data out drive	—	25.00		25.00	—	25.00	—	25.00	ns
R78	$\overline{\text{RSTCONF}}$ negated to data out high impedance	—	25.00	—	25.00	—	25.00	—	25.00	ns
R79	CLKOUT of last rising edge before chip three-state $\overline{\text{HRESET}}$ to data out high impedance	—	25.00	—	25.00	—	25.00	—	25.00	ns
R80	DSDI, DSCK setup	90.91	—	75.00	—	60.00	—	45.45	—	ns
R81	DSDI, DSCK hold time	0.00	—	0.00	—	0.00	—	0.00	—	ns
R82	$\overline{\text{SRESET}}$ negated to CLKOUT rising edge for DSDI and DSCK sample	242.42	—	200.00	—	160.00	—	121.21	—	ns

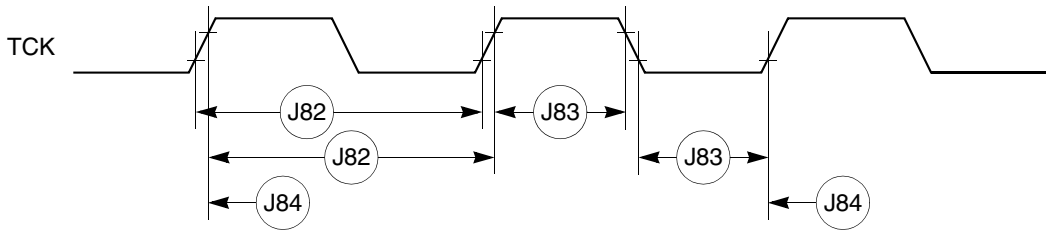


Figure 35. JTAG Test Clock Input Timing

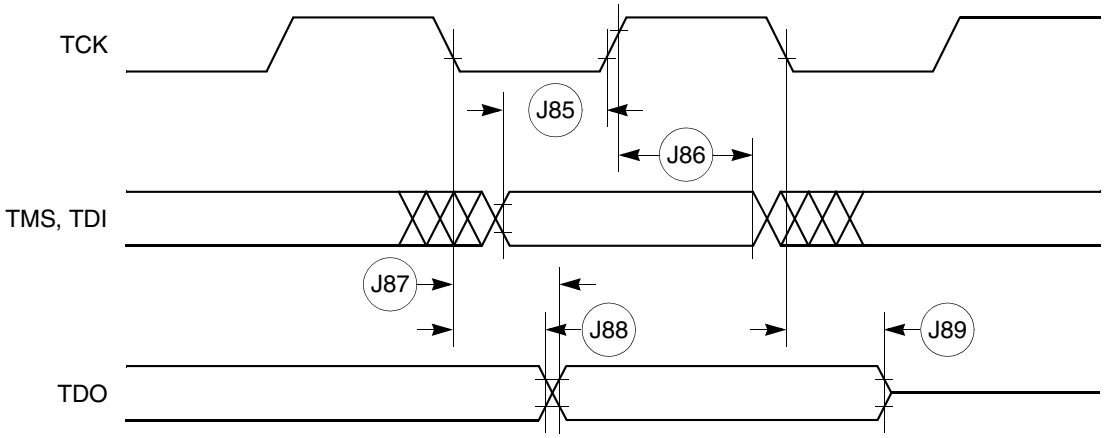


Figure 36. JTAG Test Access Port Timing Diagram

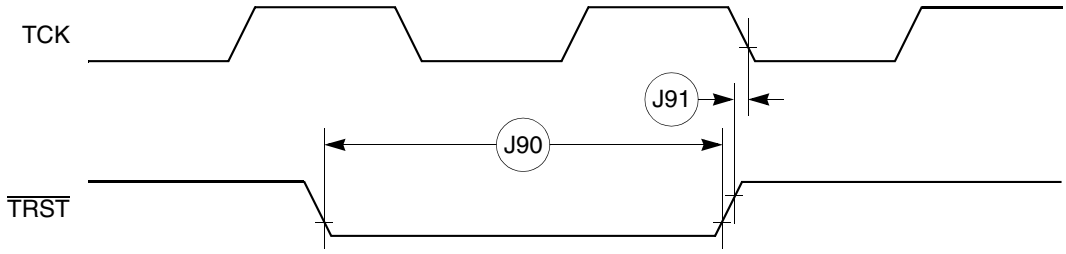


Figure 37. JTAG $\overline{\text{TRST}}$ Timing Diagram

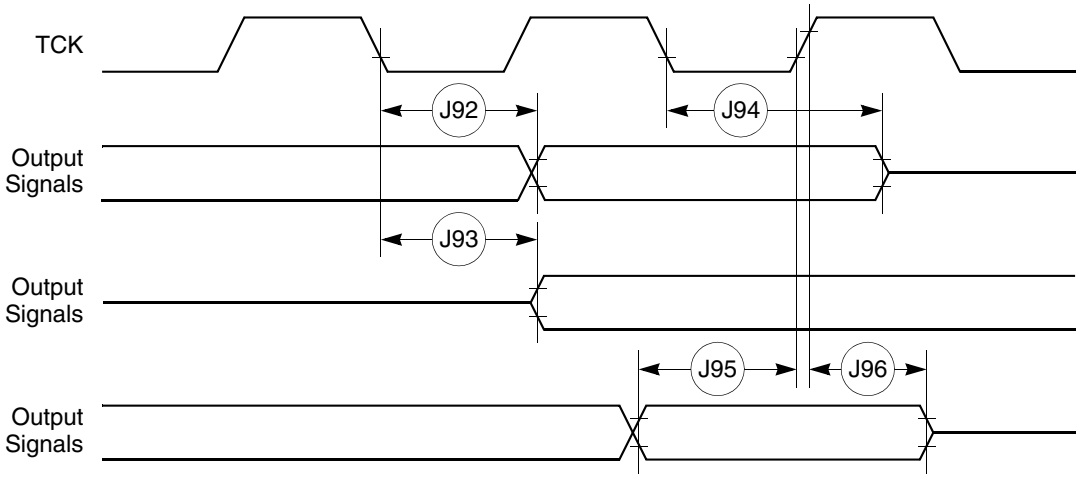


Figure 38. Boundary Scan (JTAG) Timing Diagram

11.4 Baud Rate Generator AC Electrical Specifications

Table 17 provides the baud rate generator timings as shown in Figure 49.

Table 17. Baud Rate Generator Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
50	BRGO rise and fall time	—	10	ns
51	BRGO duty cycle	40	60	%
52	BRGO cycle	40	—	ns

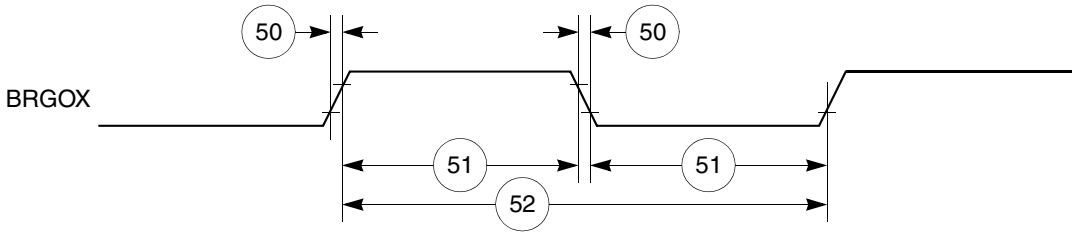


Figure 49. Baud Rate Generator Timing Diagram

11.5 Timer AC Electrical Specifications

Table 18 provides the general-purpose timer timings as shown in Figure 50.

Table 18. Timer Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
61	TIN/$\overline{\text{TGATE}}$ rise and fall time	10	—	ns
62	TIN/$\overline{\text{TGATE}}$ low time	1	—	CLK
63	TIN/$\overline{\text{TGATE}}$ high time	2	—	CLK
64	TIN/$\overline{\text{TGATE}}$ cycle time	3	—	CLK
65	CLKO low to $\overline{\text{TOUT}}$ valid	3	25	ns

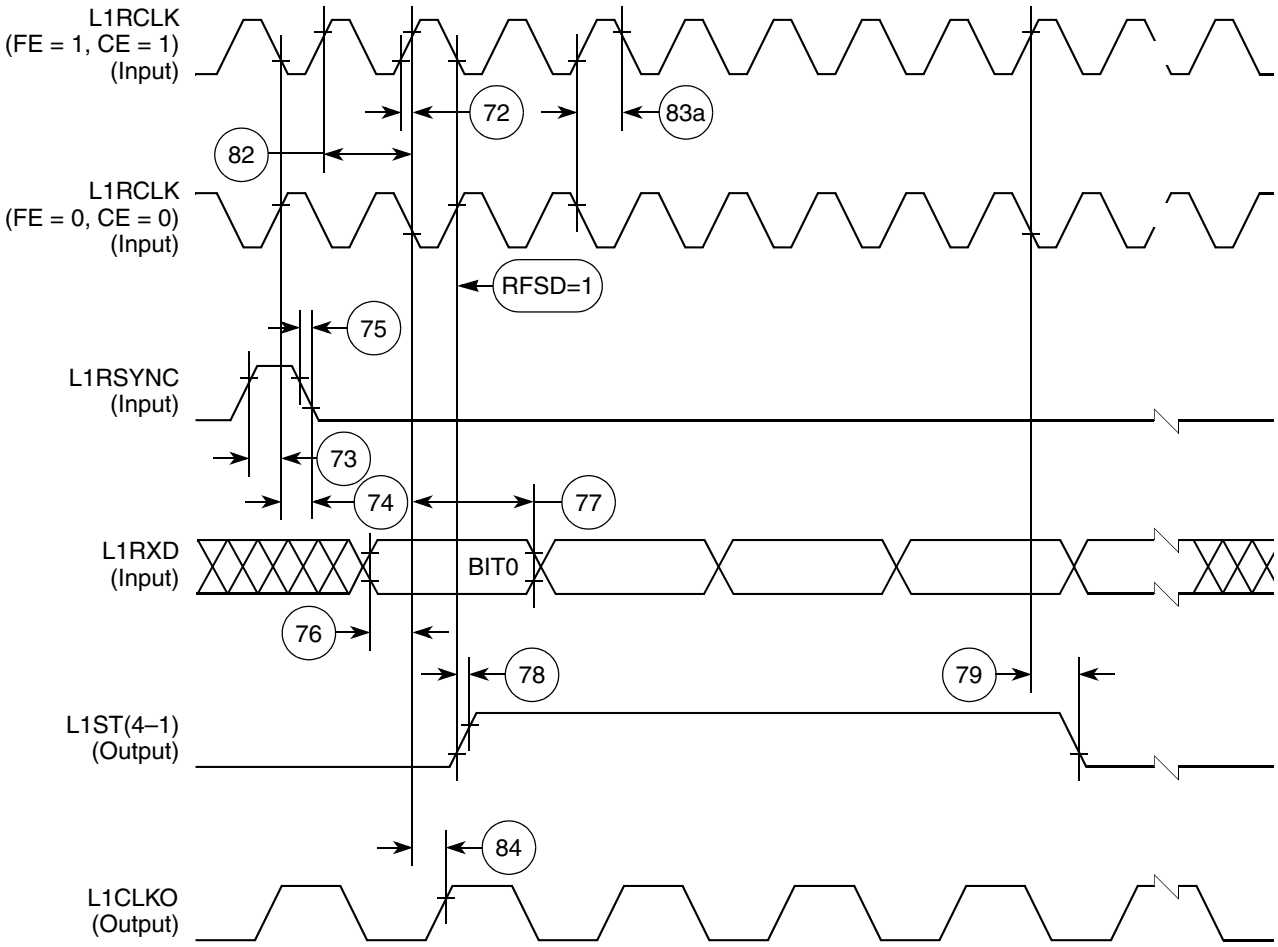


Figure 52. SI Receive Timing with Double-Speed Clocking (DSC = 1)

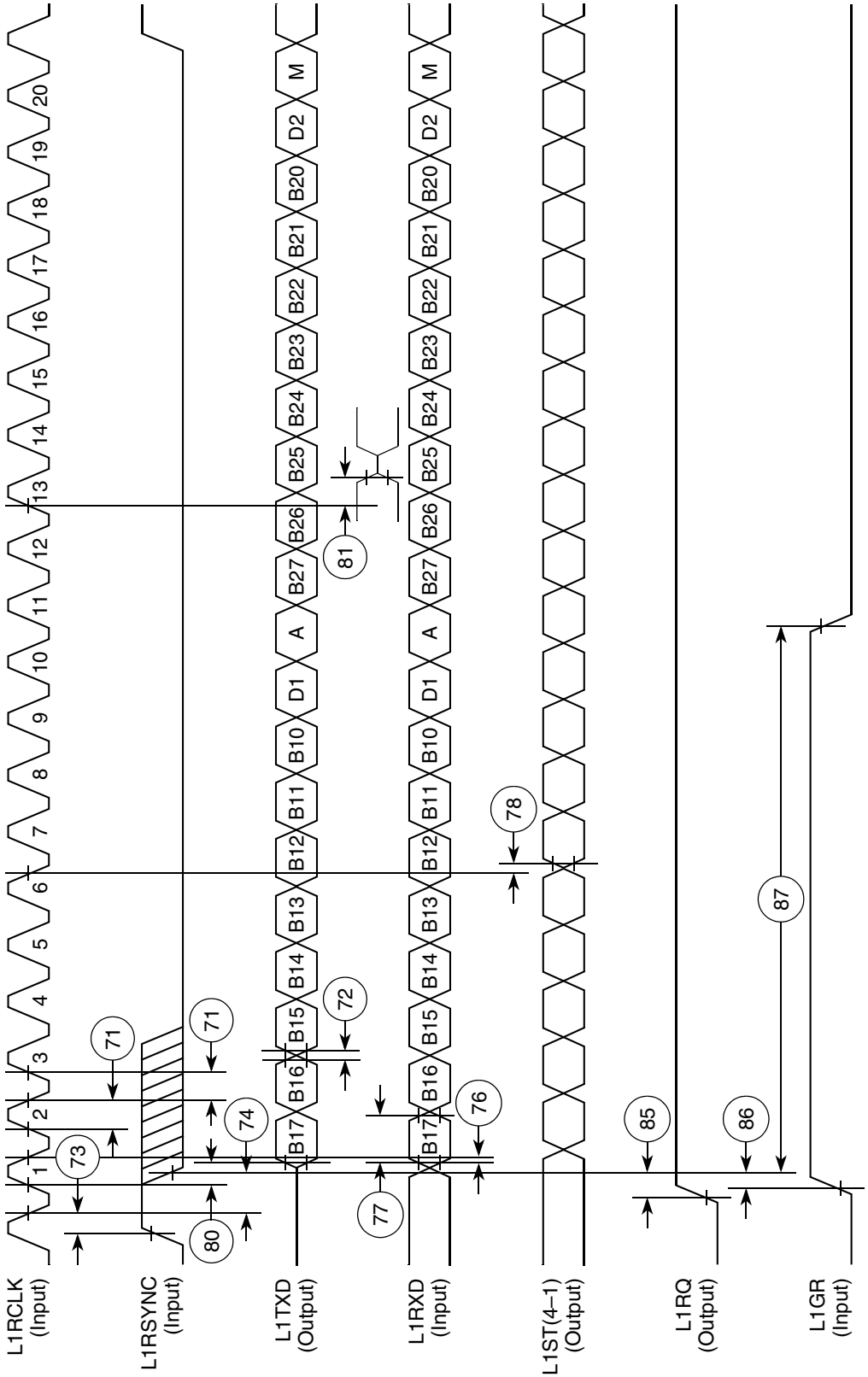


Figure 55. IDL Timing

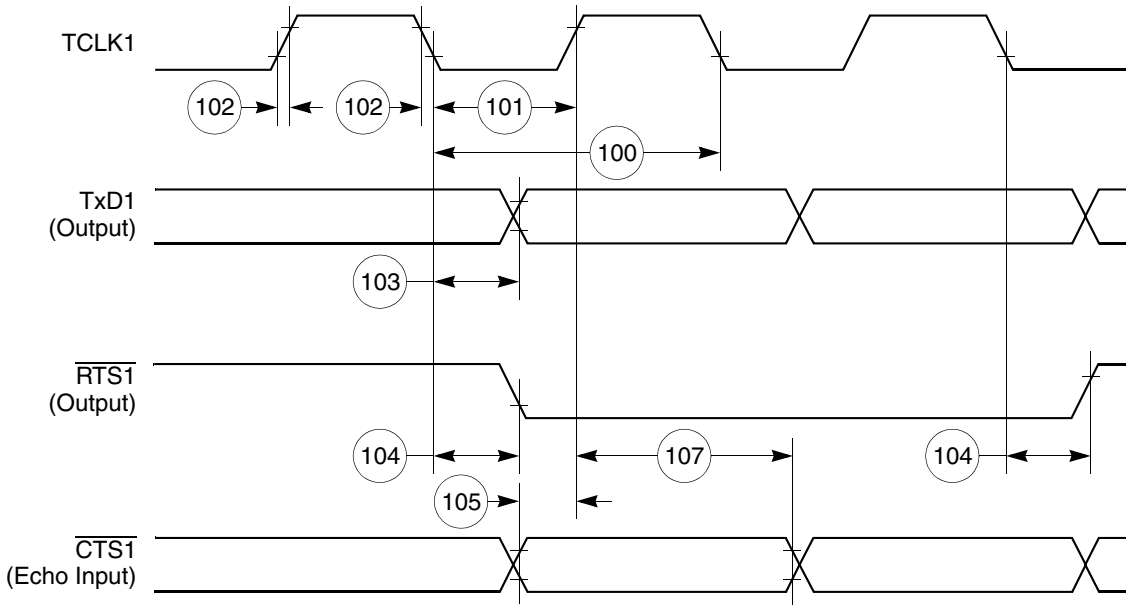


Figure 58. HDLC Bus Timing Diagram

11.8 Ethernet Electrical Specifications

Table 22 provides the Ethernet timings as shown in Figure 59 through Figure 63.

Table 22. Ethernet Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
120	CLSN width high	40	—	ns
121	RCLK1 rise/fall time	—	15	ns
122	RCLK1 width low	40	—	ns
123	RCLK1 clock period[1]	80	120	ns
124	RXD1 setup time	20	—	ns
125	RXD1 hold time	5	—	ns
126	RENA active delay (from RCLK1 rising edge of the last data bit)	10	—	ns
127	RENA width low	100	—	ns
128	TCLK1 rise/fall time	—	15	ns
129	TCLK1 width low	40	—	ns
130	TCLK1 clock period[1]	99	101	ns
131	TXD1 active delay (from TCLK1 rising edge)	10	50	ns
132	TXD1 inactive delay (from TCLK1 rising edge)	10	50	ns
133	TENA active delay (from TCLK1 rising edge)	10	50	ns
134	TENA inactive delay (from TCLK1 rising edge)	10	50	ns

11.10 SPI Master AC Electrical Specifications

Table 24 provides the SPI master timings as shown in Figure 65 and Figure 66.

Table 24. SPI Master Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
160	MASTER cycle time	4	1024	t_{cyc}
161	MASTER clock (SCK) high or low time	2	512	t_{cyc}
162	MASTER data setup time (inputs)	50	—	ns
163	Master data hold time (inputs)	0	—	ns
164	Master data valid (after SCK edge)	—	20	ns
165	Master data hold time (outputs)	0	—	ns
166	Rise time output	—	15	ns
167	Fall time output	—	15	ns

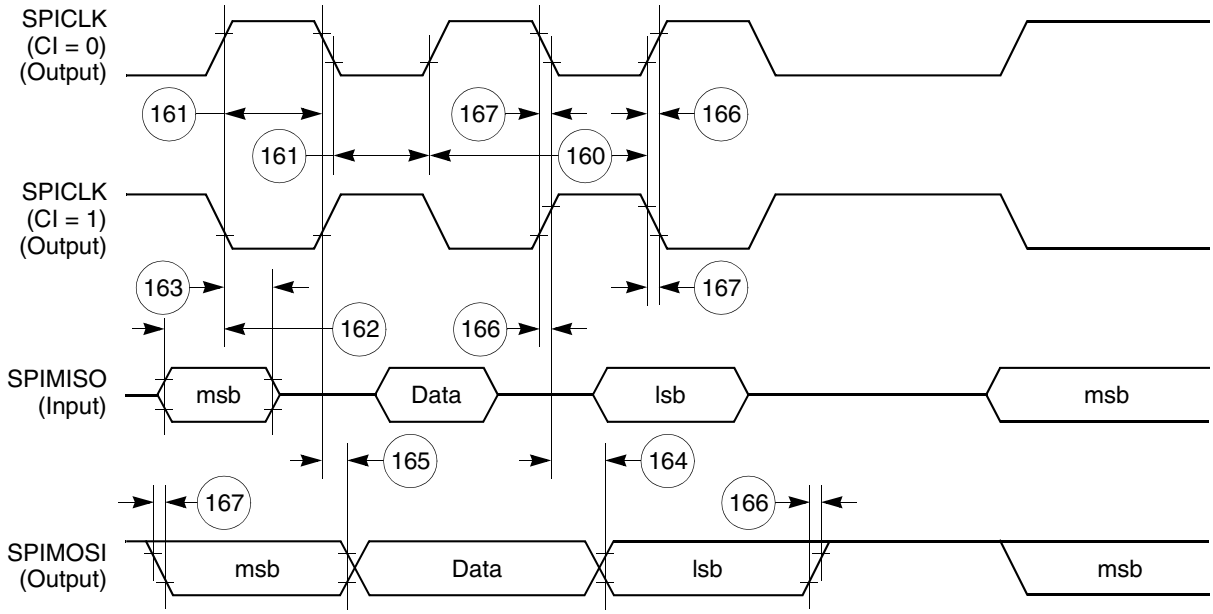


Figure 65. SPI Master (CP = 0) Timing Diagram

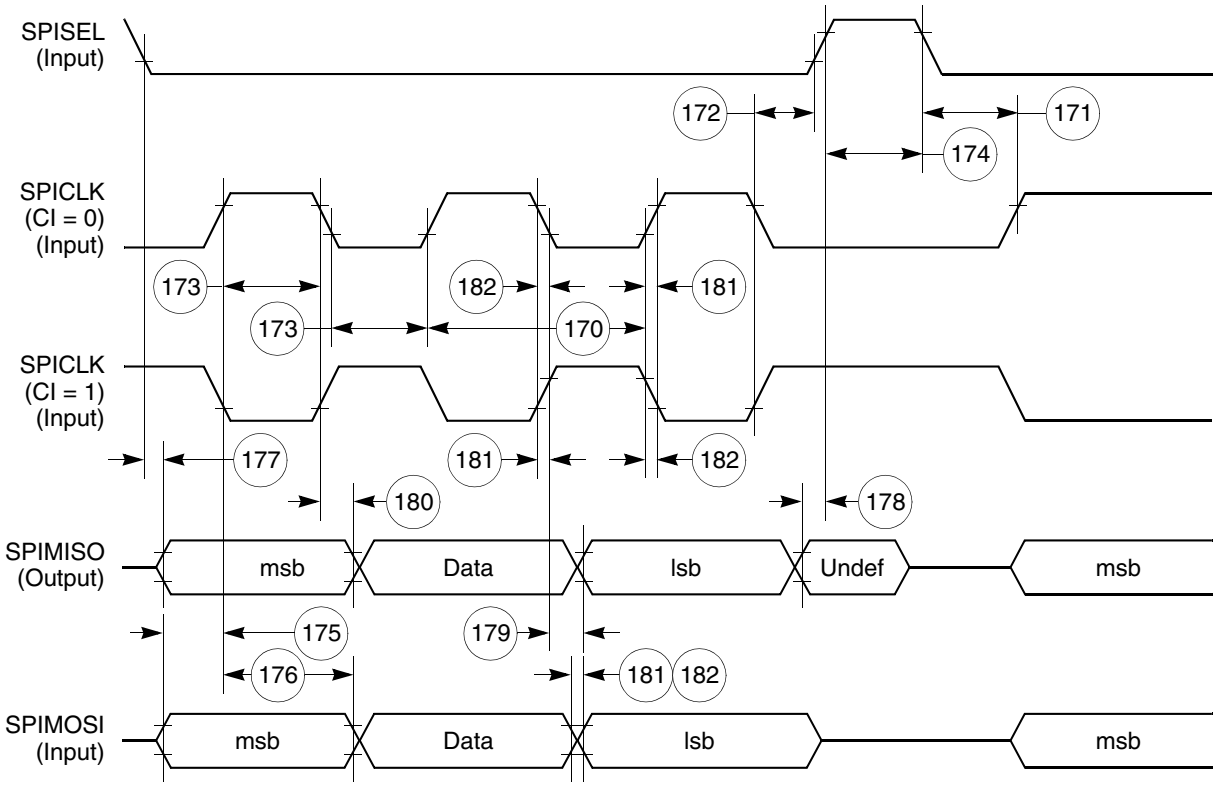


Figure 67. SPI Slave (CP = 0) Timing Diagram

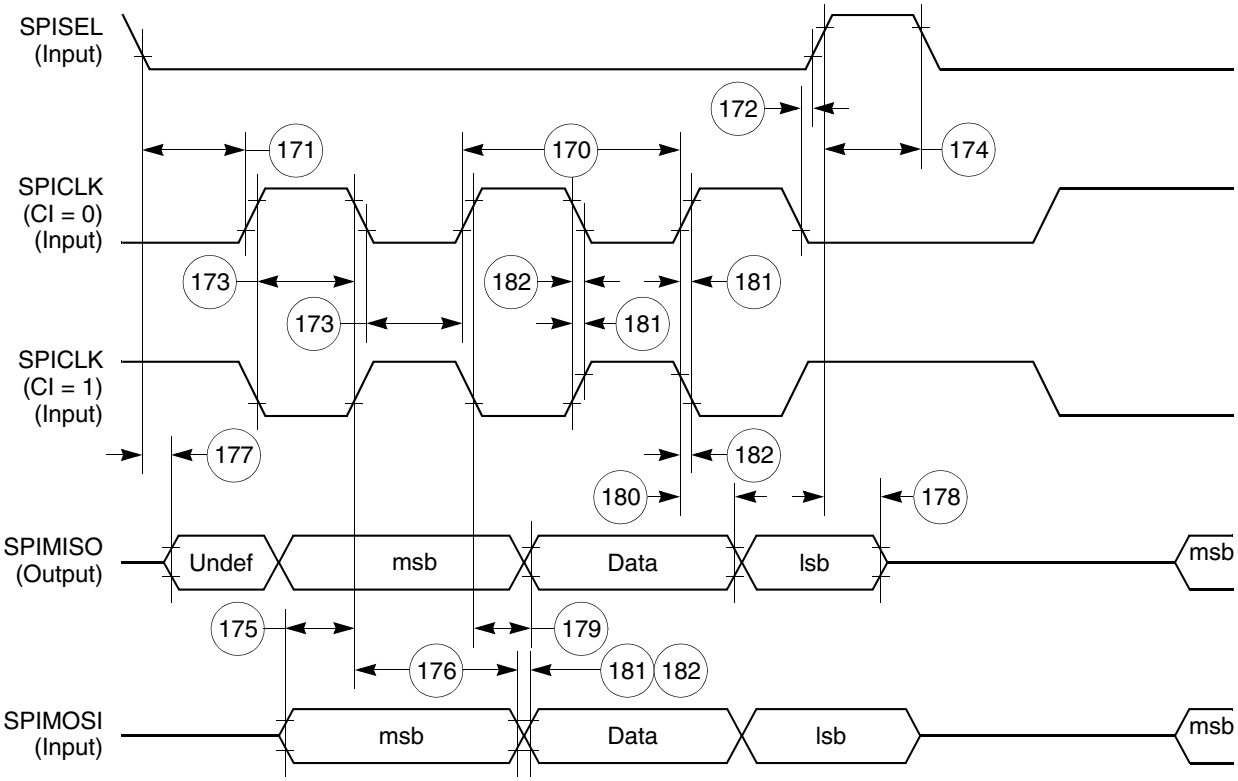


Figure 68. SPI Slave (CP = 1) Timing Diagram

11.12 I²C AC Electrical Specifications

Table 26 provides the I²C (SCL < 100 kHz) timings.

Table 26. I²C Timing (SCL < 100 kHz)

Num	Characteristic	All Frequencies		Unit
		Min	Max	
200	SCL clock frequency (slave)	0	100	kHz
200	SCL clock frequency (master)[1]	1.5	100	kHz
202	Bus free time between transmissions	4.7	—	µs
203	Low period of SCL	4.7	—	µs
204	High period of SCL	4.0	—	µs
205	Start condition setup time	4.7	—	µs
206	Start condition hold time	4.0	—	µs
207	Data hold time	0	—	µs
208	Data setup time	250	—	ns
209	SDL/SCL rise time	—	1	µs
210	SDL/SCL fall time	—	300	ns
211	Stop condition setup time	4.7	—	µs

1 SCL frequency is given by SCL = BRGCLK_frequency / ((BRG register + 3 × pre_scaler × 2).
The ratio SYNCCLK/(BRGCLK/pre_scaler) must be greater than or equal to 4/1.

Table 27 provides the I²C (SCL > 100 kHz) timings.

Table 27. . I²C Timing (SCL > 100 kHz)

Num	Characteristic	Expression	All Frequencies		Unit
			Min	Max	
200	SCL clock frequency (slave)	fSCL	0	BRGCLK/48	Hz
200	SCL clock frequency (master)[1]	fSCL	BRGCLK/16512	BRGCLK/48	Hz
202	Bus free time between transmissions		1/(2.2 * fSCL)	—	s
203	Low period of SCL		1/(2.2 * fSCL)	—	s
204	High period of SCL		1/(2.2 * fSCL)	—	s
205	Start condition setup time		1/(2.2 * fSCL)	—	s
206	Start condition hold time		1/(2.2 * fSCL)	—	s
207	Data hold time		0	—	s
208	Data setup time		1/(40 * fSCL)	—	s
209	SDL/SCL rise time		—	1/(10 * fSCL)	s
210	SDL/SCL fall time		—	1/(33 * fSCL)	s
211	Stop condition setup time		1/2(2.2 * fSCL)	—	s

1 SCL frequency is given by SCL = BRGCLK_frequency / ((BRG register + 3) × pre_scaler × 2).
The ratio SYNCCLK/(BRGCLK / pre_scaler) must be greater than or equal to 4/1.

Figure 69 shows the I^2C bus timing.

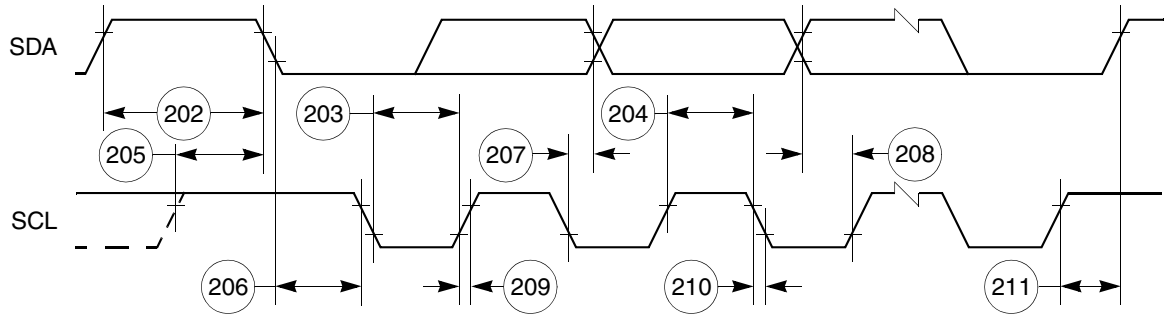


Figure 69. I^2C Bus Timing Diagram

12 UTOPIA AC Electrical Specifications

Table 28 shows the AC electrical specifications for the UTOPIA interface.

Table 28. UTOPIA AC Electrical Specifications

Num	Signal Characteristic	Direction	Min	Max	Unit
U1	UtpClk rise/fall time (Internal clock option)	Output	—	3.5	ns
	Duty cycle		50	50	%
	Frequency		—	50	MHz
U1a	UtpClk rise/fall time (external clock option)	Input	—	3.5	ns
	Duty cycle		40	60	%
	Frequency		—	50	MHz
U2	$\overline{\text{RxEnb}}$ and $\overline{\text{TxEnb}}$ active delay	Output	2	16	ns
U3	UTPB, SOC, Rxclav and Txclav setup time	Input	8	—	ns
U4	UTPB, SOC, Rxclav and Txclav hold time	Input	1	—	ns
U5	UTPB, SOC active delay (and PHREQ and PHSEL active delay in MPHY mode)	Output	2	16	ns

13.2 MII Transmit Signal Timing (MII_TXD[3:0], MII_TX_EN, MII_TX_ER, MII_TX_CLK)

The transmitter functions correctly up to a MII_TX_CLK maximum frequency of 25 MHz +1%. There is no minimum frequency requirement. In addition, the processor clock frequency must exceed the MII_TX_CLK frequency – 1%.

Table 30 provides information on the MII transmit signal timing.

Table 30. MII Transmit Signal Timing

Num	Characteristic	Min	Max	Unit
M5	MII_TX_CLK to MII_TXD[3:0], MII_TX_EN, MII_TX_ER invalid	5	—	ns
M6	MII_TX_CLK to MII_TXD[3:0], MII_TX_EN, MII_TX_ER valid	—	25	
M7	MII_TX_CLK pulse width high	35	65%	MII_TX_CLK period
M8	MII_TX_CLK pulse width low	35%	65%	MII_TX_CLK period

Figure 73 shows the MII transmit signal timing diagram.

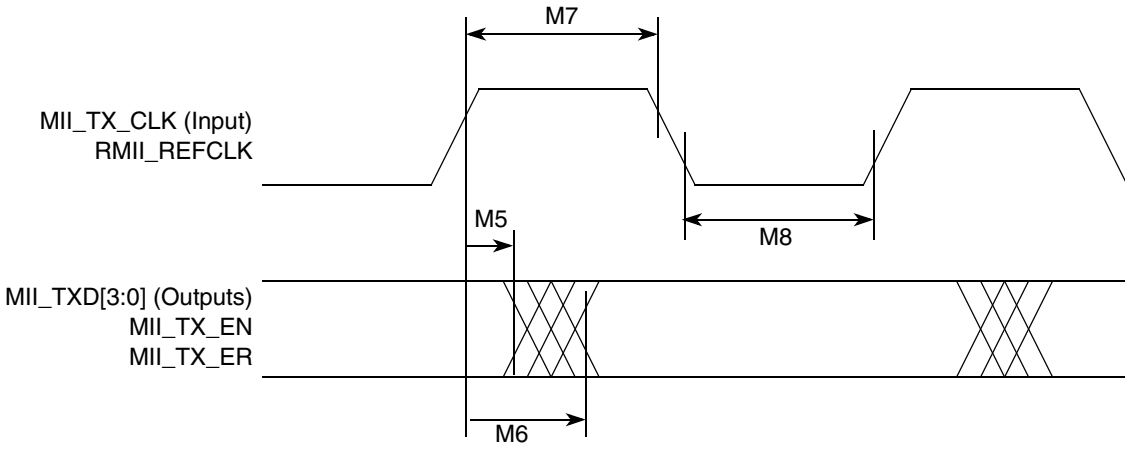


Figure 73. MII Transmit Signal Timing Diagram

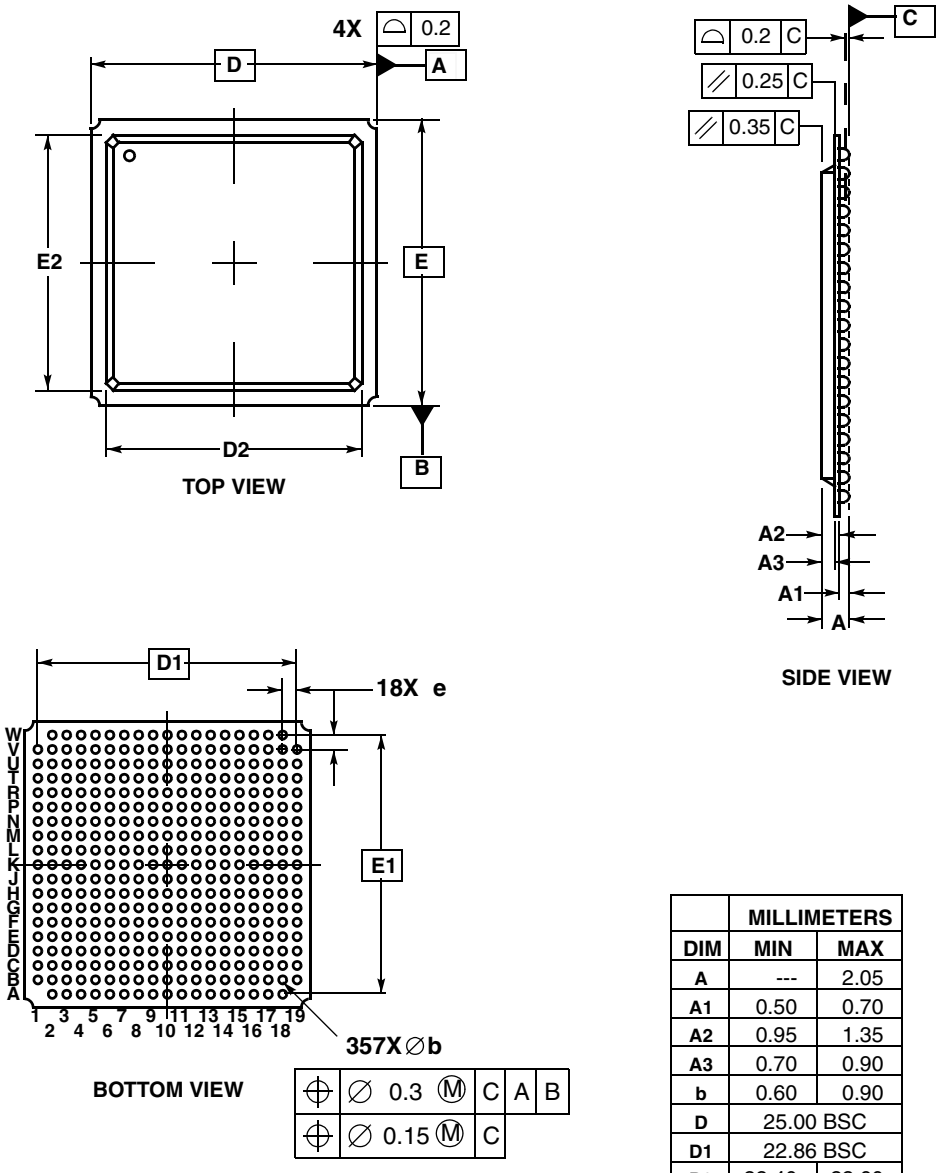
Table 34. MPC860 Family Package/Frequency Availability (continued)

Package Type	Freq. (MHz) / Temp. (Tj)	Package	Order Number
Ball grid array *(continued)* ZP suffix—leaded ZQ suffix—leaded VR suffix—lead-free	80 0° to 95°C	ZP/ZQ[1]	MPC855TZQ80D4 MPC860DEZQ80D4 MPC860DTZQ80D4 MPC860ENZQ80D4 MPC860SRZQ80D4 MPC860TZQ80D4 MPC860DPZQ80D4 MPC860PZQ80D4
		Tape and Reel	MPC860PZQ80D4R2 MPC860PVR80D4R2
		VR	MPC855TVR80D4 MPC860DEVR80D4 MPC860DPVR80D4 MPC860ENVR80D4 MPC860PVR80D4 MPC860SRVR80D4 MPC860TVR80D4
Ball grid array (CZP suffix) CZP suffix—leaded CZQ suffix—leaded CVR suffix—lead-free	50 –40° to 95°C	ZP/ZQ[1]	MPC855TCZQ50D4 MPC855TCVR50D4 MPC860DECZQ50D4 MPC860DTCZQ50D4 MPC860ENCZQ50D4 MPC860SRCZQ50D4 MPC860TCZQ50D4 MPC860DPCZQ50D4 MPC860PCZQ50D4
		Tape and Reel	MPC855TCZQ50D4R2 MC860ENCVR50D4R2
		CVR	MPC860DECVR50D4 MPC860DTCVR50D4 MPC860ENCVR50D4 MPC860PCVR50D4 MPC860SRCVR50D4 MPC860TCVR50D4
	66 –40° to 95°C	ZP/ZQ[1]	MPC855TCZQ66D4 MPC855TCVR66D4 MPC860ENCZQ66D4 MPC860SRCZQ66D4 MPC860TCZQ66D4 MPC860DPCZQ66D4 MPC860PCZQ66D4
		CVR	MPC860DTCVR66D4 MPC860ENCVR66D4 MPC860PCVR66D4 MPC860SRCVR66D4 MPC860TCVR66D4

[1] The ZP package is no longer recommended for use. The ZQ package replaces the ZP package.

14.3 Mechanical Dimensions of the PBGA Package

Figure 77 shows the mechanical dimensions of the ZP PBGA package.



	MILLIMETERS	
DIM	MIN	MAX
A	---	2.05
A1	0.50	0.70
A2	0.95	1.35
A3	0.70	0.90
b	0.60	0.90
D	25.00 BSC	
D1	22.86 BSC	
D2	22.40	22.60
e	1.27 BSC	
E	25.00 BSC	
E1	22.86 BSC	
E2	22.40	22.60

NOTE

1. Dimensions and tolerance per ASME Y14.5M, 1994.
2. Dimensions in millimeters.
3. Dimension b is the maximum solder ball diameter measured parallel to data C.

Figure 77. Mechanical Dimensions and Bottom Surface Nomenclature of the ZP PBGA Package

15 Document Revision History

Table 35 lists significant changes between revisions of this hardware specification.

Table 35. Document Revision History

Revision	Date	Changes
10	09/2015	In Table 34, moved MPC855TCVR50D4 and MPC855TCVR66D4 under the extended temperature (–40° to 95°C) and removed MC860ENCVR50D4R2 from the normal temperature Tape and Reel.
9	10/2011	Updated orderable part numbers in Table 34, “MPC860 Family Package/Frequency Availability.”
8	08/2007	• Updated template. • On page 1, added a second paragraph. • After Table 2, inserted a new figure showing the undershoot/overshoot voltage (Figure 1) and renumbered the rest of the figures. • In Figure 3, changed all reference voltage measurement points from 0.2 and 0.8 V to 50% level. • In Table 16, changed num 46 description to read, “$\overline{TA}$ assertion to rising edge ...” • In Figure 46, changed $\overline{TA}$ to reflect the rising edge of the clock.
7.0	9/2004	• Added a tablefootnote to Table 6 DC Electrical Specifications about meeting the VIL Max of the I2C Standard • Replaced the thermal characteristics in Table 4 by the ZQ package • Add the new parts to the Ordering and Availablity Chart in Table 34 • Added the mechanical spec of the ZQ package in Figure 78 • Removed all of the old revisions from Table 5
6.3	9/2003	• Added Section 11.2 on the Port C interrupt pins • Nontechnical reformatting
6.2	8/2003	• Changed B28a through B28d and B29d to show that TRLX can be 0 or 1 • Changed reference documentation to reflect the Rev 2 MPC860 PowerQUICC Family Users Manual • Nontechnical reformatting
6.1	11/2002	• Corrected UTOPIA RXenb* and TXenb* timing values • Changed incorrect usage of Vcc to Vdd • Corrected dual port RAM to 8 Kbytes
6	10/2002	• Added the MPC855T. Corrected Figure 26 on page -36.
5.1	11/2001	• Revised template format, removed references to MAC functionality, changed Table 7 B23 max value @ 66 MHz from 2ns to 8ns, added this revision history table